

Search Notes

Application/Control No.

10/602,925

Examiner

Patrick M. Buechner

Applicant(s)/Patent under
Reexamination

DELAGE, JEAN-FRANCOIS

Art Unit

3754

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 222 | 92 | 5/27/2005 | PB |
| 222 | 206 | 5/27/2005 | PB |
| 222 | 212 | 5/27/2005 | PB |
| 222 | 490 | 5/27/2005 | PB |
| 222 | 548 | 5/27/2005 | PB |
| 222 | 553 | 5/27/2005 | PB |
| 222 | 556 | 5/27/2005 | PB |
| 222 | 559 | 5/27/2005 | PB |
| 222 | 522 | 5/27/2005 | PB |
| 215 | 235 | 5/27/2005 | PB |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| inventor name and text search | 5/27/2005 | PB |
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Search Notes (continued)

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SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 220 | 252 | 5/27/2005 | PB |
| 220 | 256.1 | 5/27/2005 | PB |
| 220 | 259.1 | 5/27/2005 | PB |
| 220 | 259.3 | 5/27/2005 | PB |
| 220 | 259.5 | 5/27/2005 | PB |
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**SEARCH NOTES
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